

- single-weight set, 510
- singly-testable path-delay fault, 420
- singly-untestable path, 426
- singular cover, 177
- sink node, 407
- Sivaraman, 624
- six sigma, 439
- six sigma quality, 491
- skewed-load delay test, 431
- SL switch, 583
- slave, 212
- sleeping sickness, 295
- slew limiting, 362
- SLIC, 366
- slow clock test, 11
- slow-clock delay testing, 432
- Smith, 422
- SMT, 491, 551, 605
- Snethen, 219
- SNPSF, 258, 273, 287, 536
- SOAF, 258
- SOC, 15, 386, 605, 611, 613
- SOCRATES, 197, 204
- soft core, 606
- soft fault, 387
- soft fault test, 398
- SOFTG, 219
- SOI, 256
- solder bump, 549
- Soma, 386, 622
- Somenzi, 625
- Souders, 335
- source event, 102
- source node, 407
- source stepping, 393
- spare column, 257
- spare row, 257
- sparkle code, 327
- sparse sampling, 381
- specialization, 41
- specification, 4, 6, 7
- specification testing, 389
- specification-based test, 312
- spectra, 341
- spectral component, 342
- spectral image, 354
- spectral line power, 349
- spectral mirror image, 351
- speed binning, 21
- spike suppression, 127
- SPLIT data structure, 221
- spot delay defect, 435
- SRAM, 253
- SRU, 596
- SSQ, 349, 381
- stacked capacitor, 256
- STAFAN, 125
- Stahnke, 619
- staircasing, 320
- STALLION, 222
- standard cell, 475
- standard cell library, 94
- standard deviation, 360
- standard LFSR, 503
- standard test interface language, 607
- standby current test, 305
- STAR-BIST, 512
- star-fault, 64, 66
- state coupling fault, 258, 271
- state observation, 212
- state transition graph, 222
- statement coverage, 60, 597
- static analog test, 398
- static analysis, 129
- static burn-in, 44
- static compaction, 205
- static differential linearity, 323
- static electrical discharge, 260
- static integral linearity, 323
- static learning, 197
- static neighborhood pattern sensitive fault, 258, 273, 536
- static path sensitization, 420
- static RAM, 253
- static testing, 435
- static timing analysis, 434
- statistical fault analysis, 125
- statistical sampling, 381
- statistically independent signals, 348
- statistically orthogonal signals, 348
- steady state, 14
- STEED, 222
- STG, 222
- STIL, 607
- Stoffel, 626
- STRATEGATE, 247
- stratified sampling, 125
- strobe time, 26
- Strojwas, 624, 627
- Stroud, 534, 624
- structural analog circuit test, 406
- structural fault, 67
- structural test, 59, 78, 155, 156, 386
- structural view, 389
- structure graph, 480
- structured DFT, 467
- stuck-at fault, 65, 67, 156, 258, 267
- stuck-closed fault, 68, 446
- stuck-on fault, 14, 68
- stuck-open address decoder fault, 258
- stuck-open fault, 67, 444
- stuck-open transistor, 448
- stuck-short fault, 67, 70
- STUMPS, 522
- sub-threshold conduction, 440, 455
- sub-threshold conduction leakage, 459
- subscriber loop, 366
- subscriber loop interface circuit, 366
- substrate coupling noise, 380
- Suk, 263